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Substitute for form 1449/PTO	Complete if Known		
	Application Number	10/630,615	
INFORMATION DISCLOSURE	Filing Date	67/30/2003	
	First Named Inventor	Josey G. Angilivelil	
STATEMENT BY APPLICANT	Art Unit	2825	
(Use as many sheets as necessary)	Examiner Name	NGHIA M. DEAN	
Sheet 1 of 2	Attorney Docket Number	TI-34945	

			U. S. PATEN	T DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (F troom)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
NMD		^{US-} 5,606,567	02/25/1997	Agrawal, et al.	
NMO		^{US-} 6,131,181	10/10/2000	Bushnell, et al.	
nmo		^{US-} 6,205,559 B1	. 03/20/2001	Sakaguchi	
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		FOREI	GN PATENT DOCU	MENTS		
Examiner Initials*	Cite No.1	Foreign Patent Oocument	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	Γ.
		Country Code ³ Number ⁴ Kind Code ⁵ (# known)	MM-DD-YYYY		Or Relevant Figures Appear	To
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Substitute for form 1449/PTO		Complete If Known				
Guosia	ite ioi ioilii 14-3/F 10			Application Numb r	101630,615	
INF	ORMATION	DIS	CLOSURE	Filing Date	07/30/2003	
STA	STATEMENT BY APPLICANT		First Nam d Inventor	Josey G. Angilivelil		
	Oles as many sh			Art Unit	2828	
	(Use as many sh	DE CS (85 /	iecessary)	Examiner Name	NGHIA M. DOAN	
Sheet	2	of	2	Attorney Docket Number	TI-34945	

Examiner	Cite	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of	
Initials*	No.1	the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
NMO		SAMY R. MAKAR and EDWARD J. MCCLUSKEY, "Iddq Test Pattern Generation for Scan Chain Latches and Flip-Flops", Center for Reliable Computing Standford University, (date unknown)	
NWD		SAGAR SBADE and DUNCAN M. WALKER, "Iddq Test: Will It Survive the DSM Challenge", Department of Computer Science Texas A&M Unviersity, pp. 1-18, (date Unknown)	
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NWP		PETER C. MAXWELL and ROBERT C. AITKEN, "Test Sets and Reject Rates: All Fault Coverages ARe Not Created Equal", IEEE Design & Test of Computers, pp. 42-51, March 1993	
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Examiner	c		In U	Date	11/00/0
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